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Power quality measurement in power supply systems -
Part 2: Functional tests and uncertainty requirements

ESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

| | |
|---|--|
| See Eesti standard EVS-EN 62586-2:2017 sisaldb Euroopa standardi EN 62586-2:2017 ingliskeelset teksti. | This Estonian standard EVS-EN 62586-2:2017 consists of the English text of the European standard EN 62586-2:2017. |
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Power quality measurement in power supply systems -
Part 2: Functional tests and uncertainty requirements
(IEC 62586-2:2017)

Mesure de la qualité de l'alimentation dans les réseaux
d'alimentation - Partie 2: Essais fonctionnels et exigences
d'incertitude
(IEC 62586-2:2017)

Messung der Spannungsqualität in
Energieversorgungssystemen - Teil 2: Funktionsprüfungen
und Anforderungen an die Messunsicherheit
(IEC 62586-2:2017)

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Europäisches Komitee für Elektrotechnische Normung

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European foreword

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- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-02-25
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-08-25

This document supersedes EN 62586-2:2014.

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

| | | |
|---------------------|------|--|
| IEC 60359 | NOTE | Harmonized as EN 60359. |
| IEC 61000-4-30:2008 | NOTE | Harmonized as EN 61000-4-30:2009 ¹⁾ (not modified). |

¹⁾ Superseded by EN 61000-4-30:2015 (IEC 61000-4-30:2015): DOW = 2018-03-27.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

| <u>Publication</u> | <u>Year</u> | <u>Title</u> | <u>EN/HD</u> | <u>Year</u> |
|-------------------------|-------------|---|---------------|-------------|
| IEC 61000-2-4 | - | Electromagnetic compatibility (EMC) - Part 2-4: Environment - Compatibility levels in industrial plants for low-frequency conducted disturbances | EN 61000-2-4 | - |
| IEC 61000-4-7 | - | Electromagnetic compatibility (EMC) - Part 4-7: Testing and measurement techniques - General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto | EN 61000-4-7 | - |
| IEC 61000-4-15 | - | Electromagnetic compatibility (EMC) - Part 4-15: Testing and measurement techniques - Flickermeter - Functional and design specifications | EN 61000-4-15 | - |
| IEC 61000-4-30 | 2015 | Electromagnetic Compatibility (EMC) - Part 4-30: Testing and measurement techniques - Power quality measurement methods | EN 61000-4-30 | 2015 |
| IEC 62586-1 | 2013 | Power quality measurement in power supply systems - Part 1: Power Quality Instruments (PQI) | EN 62586-1 | 2014 |
| ISO/IEC Guide 98-3 2008 | | Uncertainty of measurement - Part 3: Guide to the expression of uncertainty in measurement (GUM:1995) | - | - |

CONTENTS

| | |
|---|----|
| FOREWORD | 9 |
| INTRODUCTION | 11 |
| 1 Scope | 12 |
| 2 Normative references | 12 |
| 3 Terms, definitions, abbreviated terms, notations and symbols | 13 |
| 3.1 General terms and definitions | 13 |
| 3.2 Terms and definitions related to uncertainty | 13 |
| 3.3 Notations | 14 |
| 3.3.1 Functions | 14 |
| 3.3.2 Symbols and abbreviated terms | 14 |
| 3.3.3 Indices | 14 |
| 4 Requirements | 14 |
| 4.1 Requirements for products complying with class A | 14 |
| 4.2 Requirements for products complying with class S | 15 |
| 5 Functional type tests common requirements | 17 |
| 5.1 General philosophy for testing | 17 |
| 5.1.1 System topology | 17 |
| 5.1.2 Stabilization time | 17 |
| 5.1.3 Measuring ranges | 17 |
| 5.1.4 Single "power-system influence quantities" | 19 |
| 5.1.5 "External influence quantities" | 21 |
| 5.1.6 Test criteria | 21 |
| 5.2 Testing procedure | 22 |
| 5.2.1 Device under test | 22 |
| 5.2.2 Testing conditions | 22 |
| 5.2.3 Testing equipment | 22 |
| 6 Functional testing procedure for instruments complying with class A according to IEC 61000-4-30 | 22 |
| 6.1 Power frequency | 22 |
| 6.1.1 General | 22 |
| 6.1.2 Measurement method | 23 |
| 6.1.3 Measurement uncertainty and measuring range | 23 |
| 6.1.4 Measurement evaluation | 24 |
| 6.1.5 Measurement aggregation | 24 |
| 6.2 Magnitude of supply voltage | 24 |
| 6.2.1 Measurement method | 24 |
| 6.2.2 Measurement uncertainty and measuring range | 24 |
| 6.2.3 Measurement evaluation | 25 |
| 6.2.4 Measurement aggregation | 25 |
| 6.3 Flicker | 27 |
| 6.4 Supply voltage interruptions, dips and swells | 27 |
| 6.4.1 General | 27 |
| 6.4.2 Check dips / interruptions in polyphase system | 35 |
| 6.4.3 Check swells in polyphase system | 37 |
| 6.5 Supply voltage unbalance | 38 |
| 6.5.1 General | 38 |

| | | |
|--------|---|----|
| 6.5.2 | Measurement method, measurement uncertainty and measuring range | 39 |
| 6.5.3 | Aggregation | 39 |
| 6.6 | Voltage harmonics | 39 |
| 6.6.1 | Measurement method | 39 |
| 6.6.2 | Measurement uncertainty and measuring range..... | 40 |
| 6.6.3 | Measurement evaluation..... | 41 |
| 6.6.4 | Measurement aggregation | 41 |
| 6.7 | Voltage interharmonics | 43 |
| 6.7.1 | Measurement method | 43 |
| 6.7.2 | Measurement uncertainty and measuring range..... | 44 |
| 6.7.3 | Measurement evaluation..... | 45 |
| 6.7.4 | Measurement aggregation | 45 |
| 6.8 | Mains signalling voltages on the supply voltage | 47 |
| 6.8.1 | Measurement method | 47 |
| 6.8.2 | Measurement uncertainty and measuring range..... | 49 |
| 6.8.3 | Aggregation | 50 |
| 6.9 | Measurement of underdeviation and overdeviation parameters | 50 |
| 6.9.1 | Measurement method | 50 |
| 6.9.2 | Measurement uncertainty and measuring range..... | 52 |
| 6.9.3 | Measurement evaluation..... | 53 |
| 6.9.4 | Measurement aggregation | 53 |
| 6.10 | Flagging..... | 56 |
| 6.11 | Clock uncertainty testing | 58 |
| 6.12 | Variations due to external influence quantities | 58 |
| 6.12.1 | General | 58 |
| 6.12.2 | Influence of temperature | 59 |
| 6.12.3 | Influence of power supply voltage..... | 61 |
| 6.13 | Rapid voltage changes (RVC) | 62 |
| 6.13.1 | RVC parameters and evaluation | 62 |
| 6.13.2 | General | 62 |
| 6.13.3 | “No RVC” tests | 64 |
| 6.13.4 | “RVC threshold and setup” test..... | 68 |
| 6.13.5 | “RVC parameters” test..... | 70 |
| 6.13.6 | “RVC polyphase” tests | 72 |
| 6.13.7 | “Voltage is in steady-state condition” tests..... | 74 |
| 6.14 | Magnitude of current..... | 77 |
| 6.15 | Harmonic current | 77 |
| 6.16 | Interharmonic currents | 77 |
| 6.17 | Current unbalance | 77 |
| 6.17.1 | General | 77 |
| 6.17.2 | Measurement method, measurement uncertainty and measuring range | 78 |
| 7 | Functional testing procedure for instruments complying with class S according to IEC 61000-4-30 | 78 |
| 7.1 | Power frequency | 78 |
| 7.1.1 | General | 78 |
| 7.1.2 | Measurement method | 79 |
| 7.1.3 | Measurement uncertainty and measuring range..... | 79 |
| 7.1.4 | Measurement evaluation..... | 80 |
| 7.1.5 | Measurement aggregation | 80 |

| | | |
|-----------------------|---|-----|
| 7.2 | Magnitude of the supply voltage..... | 80 |
| 7.2.1 | Measurement method | 80 |
| 7.2.2 | Measurement uncertainty and measuring range..... | 80 |
| 7.2.3 | Measurement evaluation..... | 81 |
| 7.2.4 | Measurement aggregation | 81 |
| 7.3 | Flicker..... | 83 |
| 7.4 | Supply voltage interruptions, dips and swells | 83 |
| 7.4.1 | General requirements | 84 |
| 7.4.2 | Check dips / interruptions in polyphase system..... | 89 |
| 7.4.3 | Check swells in polyphase system | 91 |
| 7.5 | Supply voltage unbalance | 92 |
| 7.5.1 | General | 92 |
| 7.5.2 | Measurement method, measurement uncertainty and measuring range | 93 |
| 7.5.3 | Aggregation | 93 |
| 7.6 | Voltage harmonics | 93 |
| 7.6.1 | General | 93 |
| 7.6.2 | Measurement method | 94 |
| 7.6.3 | Measurement method, measurement uncertainty and measuring range | 95 |
| 7.6.4 | Measurement evaluation..... | 96 |
| 7.6.5 | Measurement aggregation | 96 |
| 7.7 | Voltage interharmonics | 98 |
| 7.8 | Mains signalling voltages on the supply voltage | 98 |
| 7.8.1 | General | 98 |
| 7.8.2 | Measurement method | 99 |
| 7.8.3 | Measurement uncertainty and measuring range..... | 99 |
| 7.8.4 | Aggregation | 99 |
| 7.9 | Measurement of underdeviation and overdeviation parameters | 99 |
| 7.10 | Flagging..... | 99 |
| 7.11 | Clock uncertainty testing..... | 101 |
| 7.12 | Variations due to external influence quantities | 102 |
| 7.12.1 | General | 102 |
| 7.12.2 | Influence of temperature | 103 |
| 7.12.3 | Influence of power supply voltage..... | 105 |
| 7.13 | Rapid voltage changes..... | 106 |
| 7.14 | Magnitude of current | 106 |
| 7.15 | Harmonic current | 106 |
| 7.16 | Interharmonic currents | 106 |
| 7.17 | Current unbalance | 106 |
| 7.17.1 | General | 106 |
| 7.17.2 | Measurement method, measurement uncertainty and measuring range | 107 |
| 8 | Calculation of measurement uncertainty and operating uncertainty | 108 |
| Annex A (normative) | Intrinsic uncertainty and operating uncertainty, | 110 |
| A.1 | General..... | 110 |
| A.2 | Measurement uncertainty | 110 |
| A.3 | Operating uncertainty..... | 111 |
| Annex B (informative) | Overall system uncertainty | 112 |
| Annex C (normative) | Calculation of measurement and operating uncertainty for voltage magnitude and power frequency | 113 |

| | | |
|-----------------------|---|-----|
| C.1 | Selection of test points to verify operating uncertainty and uncertainty under reference conditions | 113 |
| C.2 | Class A calculation examples..... | 113 |
| C.2.1 | General | 113 |
| C.2.2 | Parameter: magnitude of supply voltage, $U_{\text{din}} = 230 \text{ V}$, 50/60Hz, rated range of temperature -25°C to $+55^{\circ}\text{C}$ | 113 |
| C.2.3 | Parameter: power frequency 50/60 Hz, rated range of temperature -25°C to $+55^{\circ}\text{C}$ | 114 |
| Annex D (informative) | Further test on dips (amplitude and phase angles changes) | 116 |
| D.1 | Phase-to-phase or phase-to-neutral testing..... | 116 |
| D.2 | Test method..... | 116 |
| Annex E (informative) | Further tests on dips (polyphase): test procedure | 118 |
| E.1 | General..... | 118 |
| E.2 | Phase voltage dips and interruptions | 119 |
| E.3 | Phase swells..... | 119 |
| Annex F (normative) | Gapless measurements of voltage amplitude and harmonics test | 121 |
| F.1 | Purpose of the test..... | 121 |
| F.2 | Test set up..... | 121 |
| F.3 | Voltage amplitude | 121 |
| F.3.1 | Test signal..... | 121 |
| F.3.2 | Result evaluation | 121 |
| F.4 | Harmonics | 122 |
| F.4.1 | Test signal..... | 122 |
| F.4.2 | Result evaluation | 122 |
| F.5 | Inter-harmonics | 123 |
| F.5.1 | Test signal..... | 123 |
| F.5.2 | Result evaluation | 123 |
| Annex G (informative) | Gapless measurements of voltage amplitude and harmonics..... | 124 |
| Annex H (informative) | Testing equipment recommendations | 133 |
| H.1 | Testing range | 133 |
| H.2 | Uncertainty and stability of source and reference meter | 133 |
| H.2.1 | Uncertainty of source and reference meter | 133 |
| H.2.2 | Stability of the source | 134 |
| H.3 | Time synchronisation | 134 |
| H.4 | Power quality functions of source and reference meter | 134 |
| H.5 | Traceability | 135 |
| Annex I (informative) | Recommendations related to a declaration of conformity (DoC) and a test report | 136 |
| I.1 | Definitions | 136 |
| I.2 | Recommendations | 136 |
| I.3 | Example of IEC 62586-1 declaration of conformity | 136 |
| I.4 | Example of IEC 62586-2 declaration | 138 |
| I.4.1 | General | 138 |
| I.4.2 | Recommendation for IEC 62586-2 test report | 139 |
| I.4.3 | Recommendation for IEC 62586-2 test summary | 140 |
| I.4.4 | Recommendation for IEC 62586-2 test equipment information | 140 |
| I.4.5 | Recommendation for IEC 62586-2 tested functions | 140 |
| Bibliography..... | | 141 |

| | |
|--|----|
| Figure 1 – Overview of test for dips according to test A4.1.1..... | 30 |
| Figure 2 – Detail 1 of waveform for test of dips according to test A4.1.1 | 31 |
| Figure 3 – Detail 2 of waveform for tests of dips according to A4.1.1 | 31 |
| Figure 4 – Detail 3 of waveform for tests of dips according to test A4.1.1..... | 32 |
| Figure 5 – Detail 1 of waveform for test of dips according to test A4.1.2 | 32 |
| Figure 6 – Detail 2 of waveform for tests of dips according to test A4.1.2..... | 33 |
| Figure 7 – Detail 1 of waveform for test of swells according to test A4.1.2 | 33 |
| Figure 8 – Detail 2 of waveform for tests of swells according to test A4.1.2 | 34 |
| Figure 9 – Sliding reference voltage test | 34 |
| Figure 10 – Sliding reference start up condition | 35 |
| Figure 11 – Detail 1 of waveform for test of polyphase dips/interruptions | 36 |
| Figure 12 – Detail 2 of waveform for test of polyphase dips/interruptions | 36 |
| Figure 13 – Detail 3 of waveform for test of polyphase dips/interruptions | 37 |
| Figure 14 – Detail 1 of waveform for test of polyphase swells | 38 |
| Figure 15 – Detail 2 of waveform for test of polyphase swells | 38 |
| Figure 16 – Flagging test for class A..... | 57 |
| Figure 17 – Clock uncertainty testing | 58 |
| Figure 18 – Example of RVC event | 62 |
| Figure 19 – A13.1.1 waveform | 65 |
| Figure 20 – A13.1.1 waveform with RVC limits and arithmetic mean | 65 |
| Figure 21 – A13.1.2 waveform | 66 |
| Figure 22 – A13.1.2 waveform with RVC limits and arithmetic means..... | 67 |
| Figure 23 – A13.1.3 waveform | 68 |
| Figure 24 – A13.1.3 waveform with RVC limits and arithmetic mean | 68 |
| Figure 25 – A13.2.1 waveform | 69 |
| Figure 26 – A13.2.1 waveform with RVC limits and arithmetic mean | 70 |
| Figure 27 – A13.3.1 waveform | 71 |
| Figure 28 – A13.3.1 waveform with RVC limits and arithmetic mean | 72 |
| Figure 29 – A13.4.1 waveform | 73 |
| Figure 30 – A13.5.1 waveform | 75 |
| Figure 31 –A13.5.1 waveform with RVC limits and arithmetic mean | 75 |
| Figure 32 – A13.5.2 waveform | 76 |
| Figure 33 – A13.5.2 waveform with RVC limits and arithmetic mean | 77 |
| Figure 34 – Detail 1 of waveform for test of dips according to test S4.1.2 | 86 |
| Figure 35 – Detail 2 of waveform for tests of dips according to test S4.1.2 | 87 |
| Figure 36 – Detail 1 of waveform for test of swells according to test S4.1.2 | 87 |
| Figure 37 – Detail 2 of waveform for tests of swells according to test S4.1.2..... | 88 |
| Figure 38 – Sliding reference voltage test | 88 |
| Figure 39 – Sliding reference start-up condition | 89 |
| Figure 40 – Detail 1 of waveform for test of polyphase dips/interruptions | 90 |
| Figure 41 – Detail 2 of waveform for test of polyphase dips/interruptions | 90 |
| Figure 42 – Detail 3 of waveform for test of polyphase dips/interruptions | 91 |

| | |
|--|-----|
| Figure 43 – Detail 1 of waveform for test of polyphase swells | 92 |
| Figure 44 – Detail 2 of waveform for test of polyphase swells | 92 |
| Figure 45 – Flagging test for class S..... | 101 |
| Figure 46 – Clock uncertainty testing | 102 |
| Figure A.1 – Different kinds of uncertainties..... | 110 |
| Figure D.1 – Phase-to-neutral testing on three-phase systems | 116 |
| Figure D.2 – Phase-to-phase testing on three-phase systems..... | 116 |
| Figure E.1 – Example for one phase of a typical N cycle injection | 118 |
| Figure E.2 – Dip/interruption accuracy (amplitude and timing) test..... | 119 |
| Figure E.3 – Swell accuracy (amplitude and timing) test | 120 |
| Figure G.1 – Simulated signal under noisy conditions | 124 |
| Figure G.2 – Waveform for checking gapless RMS voltage measurement | 125 |
| Figure G.3 – 2,3 Hz frequency fluctuation | 125 |
| Figure G.4 – Spectral leakage effects for a missing sample | 126 |
| Figure G.5 – Illustration of \mathcal{Q}_{RMS} for missing samples..... | 127 |
| Figure G.6 – Detection of a single missing sample..... | 127 |
| Figure G.7 – \mathcal{Q}_{RMS} for an ideal signal, sampling error = -300×10^{-6} | 128 |
| Figure G.8 – \mathcal{Q}_{RMS} for an ideal signal, sampling error = 400×10^{-6} | 128 |
| Figure G.9 – \mathcal{Q}_{RMS} for an ideal signal, sampling error = 200×10^{-6} | 129 |
| Figure G.10 – $\mathcal{Q}_{\text{H}}(5)$ with ideal test signal and perfect sampling frequency synchronization..... | 130 |
| Figure G.11 – $\mathcal{Q}_{\text{H}}(5)$ with 300×10^{-6} sampling frequency error and 100×10^{-6} modulation frequency error | 130 |
| Figure G.12 – \mathcal{Q}_{RMS} with a 20/24-cycle sliding window with an output every 10/12 cycles | 131 |
| Figure G.13 – Amplitude test for fluctuating component | 131 |
| | |
| Table 1 – Summary of type tests for class A | 15 |
| Table 2 – Summary of type tests for class S | 16 |
| Table 3 – Testing points for each measured parameter | 18 |
| Table 4 – List of single "power-system influence quantities"..... | 20 |
| Table 5 – Influence of temperature | 21 |
| Table 6 – Influence of auxiliary power supply voltage..... | 21 |
| Table 7 – List of generic test criteria | 22 |
| Table 8 – Specification of test A13.1.1 | 64 |
| Table 9 – Specification of test A13.1.2 | 66 |
| Table 10 – Specification of test A13.1.3 | 67 |
| Table 11 – Specification of test A13.2.1 | 69 |
| Table 12 – Specification of test A13.3.1 | 71 |
| Table 13 – Specification of test A13.4.1 | 73 |
| Table 14 – Specification of test A13.5.1 | 74 |
| Table 15 – Specification of test A13.5.2 | 76 |
| Table 16 – Uncertainty requirements | 109 |
| Table D.1 – Tests pattern | 117 |

| | |
|---|-----|
| Table H.1 – Testing range..... | 133 |
| Table H.2 – Uncertainty of source and reference meter..... | 134 |
| Table H.3 – Stability of source | 134 |
| Table I.1 – Example of a DoC related to compliance with IEC 62586-1 | 137 |
| Table I.2 – Example of DoC related to compliance with IEC 62586-2 | 139 |

INTRODUCTION

Power quality is more and more important worldwide in power supply systems and is generally assessed by power quality instruments.

This part of IEC 62586 specifies functional and uncertainty tests intended to verify the compliance of a product to class A and class S measurement methods defined in IEC 61000-4-30.

This document therefore complements IEC 61000-4-30.